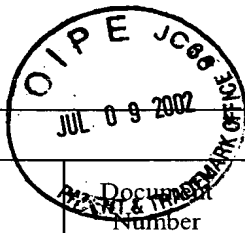


| FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary) | | | | Attorney Docket Number 5308-157IP2 | | Serial No. 10/045,542 | |
|---|----|--|----------|---------------------------------------|-------|--------------------------|----------------------------|
|  | | | | Applicants: Das et al. | | | |
| | | | | Filing Date: October 26, 2001 | | Group 1762 | |
| U. S. PATENT DOCUMENTS | | | | | | | |
| Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date if Appropriate |
| 7 | 1 | 5,885,870A | 3/99 | Maiti et al. | 438 | 261 | |
| 7 | 2 | 6,096,607 | 8/1/00 | Ueno | 438 | 522 | |
| 7 | 3 | 6,117,735 | 9/12/00 | Ueno | 438 | 268 | |
| 7 | 4 | 6,204,203 | 3/01 | Narwanker et al. | 438 | 785 | |
| 7 | 5 | 6,211,035 | 4/01 | Moise et al. | 438 | 396 | |
| 7 | 6 | US200100055 852A1 | 12/01 | Moise et al. | 438 | 396 | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation Yes No |
| 7 | 7 | DE 198 09 554 | 9/10/98 | Germany ✓ | — | — | Abstract |
| 7 | 8 | DE 19900171 | 12/26/00 | Germany ✓ | — | — | Abstract |
| 7 | 9 | DE 10036208 | 2/14/02 | Germany ✓ | — | — | Abstract |
| 7 | 10 | JP 08264766 | 10/11/96 | Japan ✓ | — | — | Abstract |
| 7 | 11 | JP 2000082812 | 3/21/00 | Japan ✓ | — | — | Abstract |
| 7 | 12 | JP 11261061 | 9/24/99 | Japan ✓ | — | — | Abstract |
| 7 | 13 | JP 11238742 | 8/31/99 | Japan ✓ | — | — | Abstract |
| 7 | 14 | JP 11266017 | 9/28/99 | Japan ✓ | — | — | Abstract |
| 7 | 15 | JP 11274487 | 10/8/99 | Japan ✓ | — | — | Abstract |
| 7 | 16 | JP 2000049167 | 2/18/00 | Japan ✓ | — | — | Abstract |
| 7 | 17 | JP 2000106371 | 4/11/01 | Japan ✓ | — | — | Abstract |
| 7 | 18 | JP 03157974 | 7/5/91 | Japan ✓ | — | — | Abstract |
| 7 | 19 | JP 09205202 | 8/5/97 | Japan ✓ | — | — | Abstract |
| 7 | 20 | JP 11191559 | 7/13/99 | Japan ✓ | — | — | Abstract |
| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| 7 | 21 | Chakraborty et al. "Interface Properties of N ₂ O-annealed SiO ₂ /SiC system," <i>Proceedings IEEE Hong Kong Electron Devices Meeting</i> . June 24, 2000, pp. 108-11. | | | | | |

| | | | |
|--|----|---|--------------------------|
| FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary) | | Attorney Docket Number 5308-157IP2 | Serial No. 10/045,542 |
| | | Applicants: Das et al. | |
| | | Filing Date: October 26, 2001 | Group 1762 |
| 7 | 22 | Lipkin et al. "Insulator Investigation on SiC for Improved Reliability," <i>IEEE Transactions on Electron Devices</i> . Vol. 46, No. 3, March 1999, pp. 525-32. | |
| 7 | 23 | Copy of International Search Report for PCT/US01/30715. | |

Michael Barr

11/12/02

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